

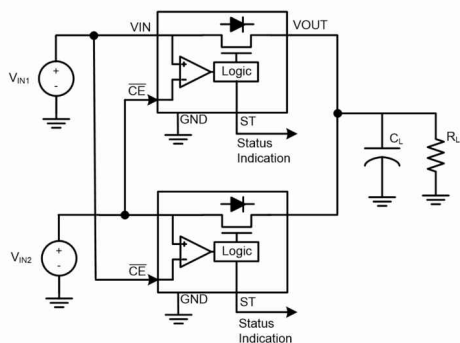
LM66100-Q1 具有输入极性保护功能的 5.5V、1.5A、79mΩ、汽车类低 IQ 理想二极管

1 特性

- 符合面向汽车应用的 AEC-Q100 标准：
 - 器件温度等级 1：-40°C 至 125°C 环境温度工作温度范围
- 宽工作电压范围：1.5V 至 5.5V
- VIN 反向关断电压：
 - 绝对最大值为 -6V
- 最大持续电流 (I_{MAX})：1.5A
- 导通电阻 (R_{ON})：
 - 5V V_{IN} = 79mΩ (典型值)
 - 3.6V V_{IN} = 91mΩ (典型值)
 - 1.8V V_{IN} = 141mΩ (典型值)
- 启用比较器芯片 (CE)
- 通道状态指示 (ST)
- 低电流消耗：
 - 3.6V V_{IN} 关断电流 (I_{SD,VIN})：120nA (典型值)
 - 3.6V V_{IN} 静态电流 (I_{Q,VIN})：150nA (典型值)

2 应用

- 信息娱乐系统、仪表组和音响主机
- 汽车仪表组显示器
- ADAS 环视系统 ECU
- 车身控制模块和网关



典型应用

3 说明

LM66100-Q1 是一款单输入单输出 (SISO) 集成式理想二极管，是各种应用的理想之选。该器件包含一个可在 1.5V 至 5.5V 输入电压范围内运行的 P 沟道 MOSFET，并且支持 1.5A 的最大持续电流。

该芯片通过比较 CE 引脚电压和输入电压来提供支持。当 CE 引脚电压高于输入电压时，该器件被禁用并且 MOSFET 关断。当 CE 引脚电压比较低时，MOSFET 开启。LM66100-Q1 还具有反极性保护 (RPP) 功能，可保护器件不受输入接线错误的影响，例如电池装反。

可在 ORing 配置中使用两个 LM66100-Q1 器件，其实施方法与双二极管 ORing 相似。在此配置中，该器件将最高输入电压传递到输出端，同时阻断反向电流流入输入电源。这些器件可比较输入和输出电压，从而确保内部电压比较器成功阻断反向电流。

LM66100-Q1 采用标准 SC-70 封装，工作结温范围为 -40°C 至 150°C。

器件信息⁽¹⁾

器件型号	封装	封装尺寸 (标称值)
LM66100-Q1	SC-70 (6)	2.1mm × 2.0mm

(1) 如需了解所有可用封装，请参阅数据表末尾的可订购产品附录。



Table of Contents

1 特性	1	8.3 Feature Description.....	11
2 应用	1	8.4 Device Functional Modes.....	12
3 说明	1	9 Application and Implementation	12
4 Revision History	2	9.1 Application Information.....	12
5 Pin Configuration and Functions	3	9.2 Typical Applications.....	12
6 Specifications	4	10 Power Supply Recommendations	15
6.1 Absolute Maximum Ratings.....	4	11 Layout	16
6.2 ESD Ratings.....	4	11.1 Layout Guidelines.....	16
6.3 Recommended Operating Conditions.....	4	11.2 Layout Example.....	16
6.4 Thermal Information.....	4	12 Device and Documentation Support	17
6.5 Electrical Characteristics.....	5	12.1 Receiving Notification of Documentation Updates..	17
6.6 Switching Characteristics.....	6	12.2 支持资源.....	17
6.7 Typical Characteristics.....	7	12.3 Trademarks.....	17
7 Parameter Measurement Information	9	12.4 Electrostatic Discharge Caution.....	17
8 Detailed Description	10	12.5 术语表.....	17
8.1 Overview.....	10	13 Mechanical, Packaging, and Orderable Information	17
8.2 Functional Block Diagram.....	10		

4 Revision History

注：以前版本的页码可能与当前版本的页码不同

Changes from Revision * (November 2021) to Revision A (March 2022)	Page
• 将数据表状态从“预告信息”更改为“量产数据”	1

5 Pin Configuration and Functions

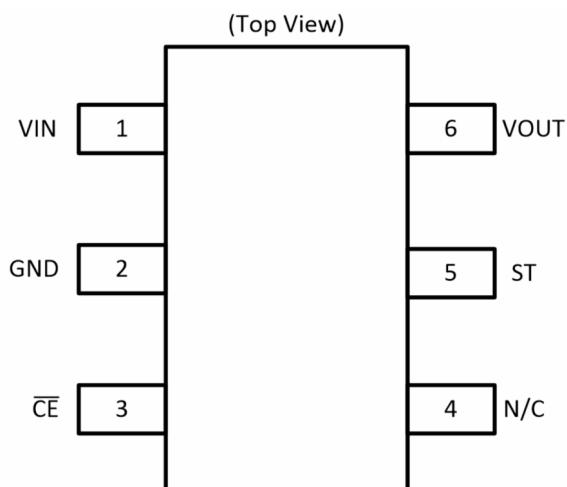


图 5-1. DCK Package 6-Pin SC-70 Top View

表 5-1. Pin Functions

PIN		I/O	DESCRIPTION
NO.	NAME		
1	VIN	I	Device input
2	GND	—	Device ground
3	$\overline{CE}$	I	Active-low chip enable. Can be connected to VOUT for reverse current protection. Do not leave floating.
4	N/C	—	Not internally connected, can be tied to GND or left floating.
5	ST	O	Active-low open-drain output, pulled low when the chip is disabled. Hi-Z when the chip is enabled. Connect to GND if not required.
6	VOUT	O	Device output

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) ⁽¹⁾

		MIN	MAX	UNIT
V _{IN}	Maximum Input Voltage Range	– 6	6	V
V _{OUT}	Maximum Output Voltage Range	– 0.3	6	V
V _{CE}	Maximum CE Pin Voltage	– 0.3	6	V
V _{ST}	Maximum ST Pin Voltage	– 0.3	6	V
I _{SW, MAX}	Maximum Continuous Switch Current		1.5	A
I _{SW, PLS}	Maximum Pulsed Switch Current (≤ 120 ms, 2% Duty Cycle)		2.5	A
I _{D, PLS}	Maximum Pulsed Body Diode Current (≤ 0.1 ms, 0.2% Duty Cycle)		2.5	A
I _{CE}	Maximum CE Pin Current	– 1		mA
I _{ST}	Maximum ST Pin Current	– 1		mA
T _J	Junction temperature	– 40	150	°C
T _{STG}	Storage temperature	– 65	150	°C
T _{LEAD}	Maximum Lead Temperature (10 s soldering time)		300	°C

- (1) Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If used outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.

6.2 ESD Ratings

			VALUE	UNIT
V _(ESD)	Electrostatic discharge	Human body model (HBM), per AEC Q100-002 ⁽¹⁾	±2000	V
		HBM ESD classification level 2		
		Charged device model (CDM), per AEC Q100-011	±500	
		CDM ESD classification level C4A		

- (1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	TYP	MAX	UNIT
V _{IN}	Input Voltage Range	1.5		5.5	V
V _{OUT}	Output Voltage Range	1		5.5	V
V _{CE}	CE Pin Voltage Range	0		5.5	V
V _{ST}	ST Pin Voltage Range	0		5.5	V

6.4 Thermal Information

THERMAL METRIC ⁽¹⁾		LM66100	UNIT
		DCK (SC-70)	
		6 PINS	
R _{θJA}	Junction-to-ambient thermal resistance	192	°C/W
R _{θJC(top)}	Junction-to-case (top) thermal resistance	124	°C/W
R _{θJB}	Junction-to-board thermal resistance	52	°C/W
Ψ _{JT}	Junction-to-top characterization parameter	34	°C/W

THERMAL METRIC ⁽¹⁾		LM66100	UNIT
		DCK (SC-70)	
		6 PINS	
Ψ_{JB}	Junction-to-board characterization parameter	52	°C/W

(1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

6.5 Electrical Characteristics

Typical values are at 25°C with an input voltage of 3.6V. Maximum and minimum values are across the entire operating voltage range, from 1.5V to 5.5V. (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
Input Supply (VIN)							
ISD,VIN	VIN Shutdown Current	VOUT = VIN VCE > VIN + 80 mV IOUT = 0 A (VOUT = open)	25°C	0.12	0.3	μA	
			- 40°C to 125°C		0.3	μA	
IQ,VIN	VIN Quiescent Current	VOUT = VIN VCE < VIN - 250 mV IOUT = 0 A (VOUT = open)	25°C	0.15	0.3	μA	
			- 40°C to 125°C		0.3	μA	
IOUT, OFF	OUT to IN Leakage Current (Current out of VIN)	VOUT - VIN ≤ 5.5 V VCE > VIN + 80 mV	25°C	0.2	0.5	μA	
			- 40°C to 85°C		2.7	μA	
			- 40°C to 125°C		8	μA	
		VOUT - VIN ≤ 4.5 V VCE > VIN + 80 mV	- 40°C to 85°C		1.7	μA	
			- 40°C to 125°C		5.1	μA	
		VOUT - VIN ≤ 1.0 V VCE > VIN + 80 mV	- 40°C to 85°C		0.7	μA	
	- 40°C to 125°C		2.1	μA			
ON-Resistance (RON)							
RON	ON-State Resistance	IOUT = - 200 mA	VIN = 5 V	25°C	79	95	m Ω
				- 40°C to 85°C		110	
				- 40°C to 125°C		120	
RON	ON-State Resistance	IOUT = - 200 mA	VIN = 3.6 V	25°C	91	110	m Ω
				- 40°C to 85°C		125	
				- 40°C to 125°C		140	
RON	ON-State Resistance	IOUT = - 200 mA	VIN = 1.8 V	25°C	141	180	m Ω
				- 40°C to 85°C		210	
				- 40°C to 125°C		230	
Comparator Chip Enable (CE)							
VON	Turn ON Threshold	VCE - VIN	- 40°C to 125°C	250	150	80	mV
VOFF	Turn OFF Threshold	VCE - VIN	- 40°C to 125°C	0	35	80	mV
ICE	CE Pin Leakage Current	VCE < VIN - 250 mV	- 40°C to 125°C	0	160	300	nA
ICE	CE Pin Leakage Current	VCE > VIN + 80 mV	- 40°C to 125°C	0	400	610	nA
Reverse Current Blocking (RCB) and Body Diode Characteristics							
IRCB	Reverse Activation Current	VCE = VOUT	- 40°C to 125°C	0.5	1		A
VFWD	Body Diode Forward Voltage	IOUT = 10 mA VCE > VIN + 80 mV	- 40°C to 125°C	0.1	0.5	1.1	V
Status Indication (ST)							
VOL, ST	Output Low Voltage	IST = 1 mA	40°C to 125°C		0.1		V

6.5 Electrical Characteristics (continued)

Typical values are at 25°C with an input voltage of 3.6V. Maximum and minimum values are across the entire operating voltage range, from 1.5V to 5.5V. (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
t _{ST}	Status Delay Time	V _{CE} transitions from low to high	– 40°C to 125°C		1		μs
I _{ST}	ST Pin Leakage Current	V _{CE} < V _{IN} – 250 mV	– 40°C to 125°C	– 20		20	nA

6.6 Switching Characteristics

Unless otherwise noted, the typical characteristics in the following table applies over the entire recommended operating voltage at an ambient temperature of 25°C and a load of C_L = 100 nF and R_L = 1 kΩ

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{ON}	Turn ON Time	V _{IN} = 1.8 V		90		μs
		V _{IN} = 3.6 V		40		μs
		V _{IN} = 5 V		27		μs
t _{OFF}	Turn OFF Time	V _{IN} = 1.8 V		2		μs
		V _{IN} = 3.6 V		2		μs
		V _{IN} = 5 V		2		μs
t _{FALL}	Output Fall Time	V _{IN} = 1.8 V		20		μs
		V _{IN} = 3.6 V		10		μs
		V _{IN} = 5 V		7.5		μs

6.7 Typical Characteristics

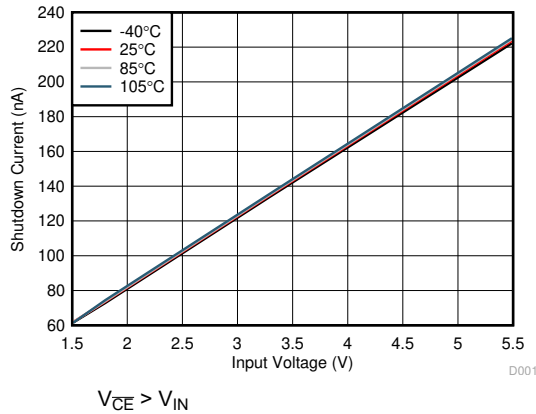


图 6-1. Shutdown Current vs Input Voltage

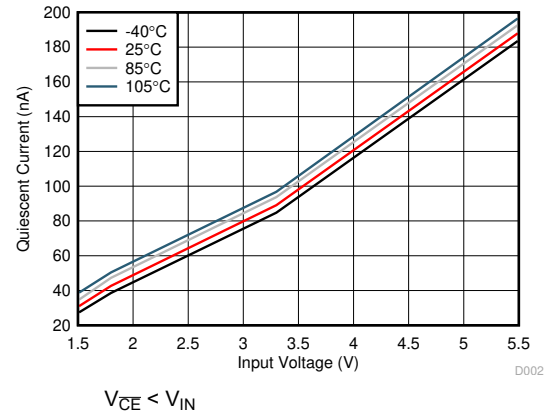


图 6-2. Quiescent Current vs Input Voltage

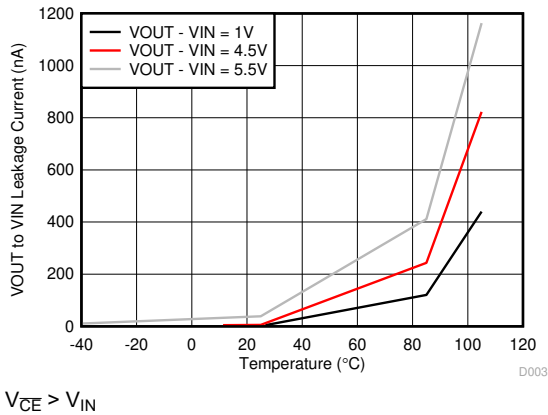


图 6-3. Reverse Leakage Current vs Junction Temperature

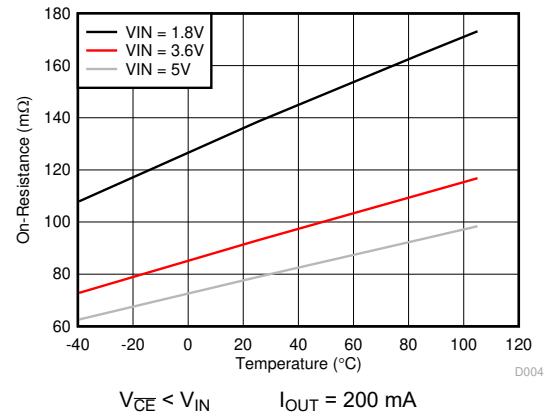


图 6-4. On-Resistance vs Junction Temperature

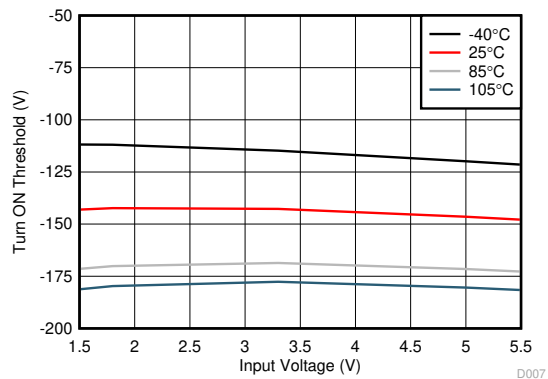


图 6-5. Turn ON Threshold vs Input Voltage

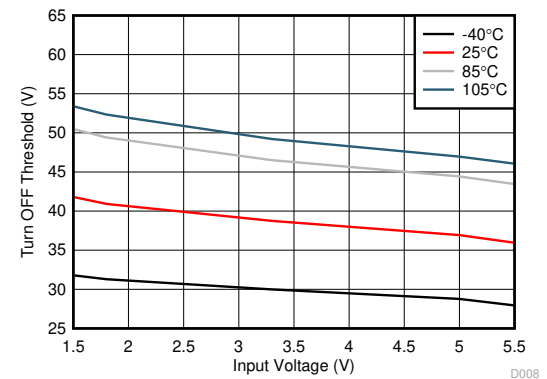


图 6-6. Turn OFF Threshold vs Input Voltage

6.7 Typical Characteristics (continued)

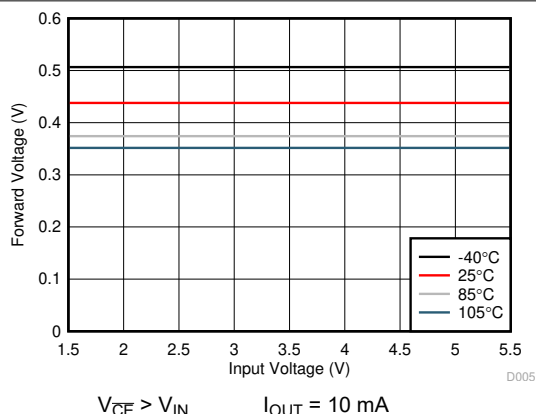


图 6-7. Body Diode Forward Voltage vs Input Voltage

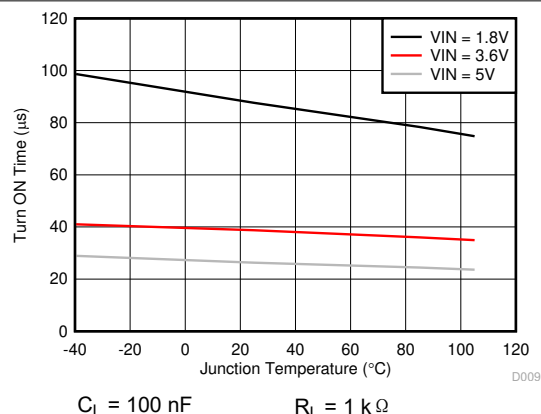


图 6-8. Turn ON Time vs Junction Temperature

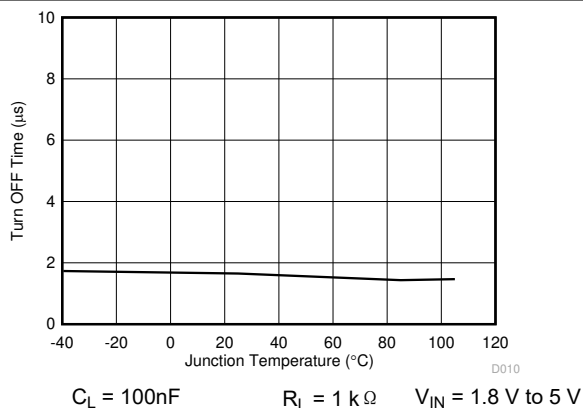


图 6-9. Turn OFF Time vs Junction Temperature

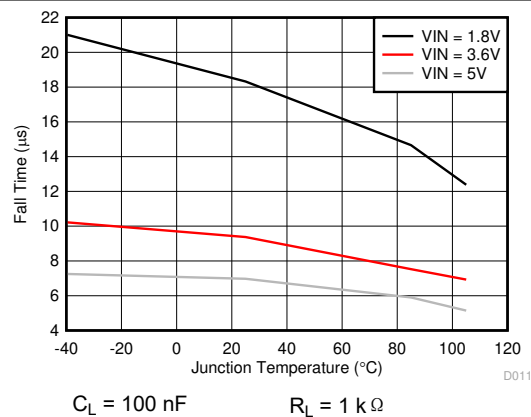


图 6-10. Fall Time vs Junction Temperature

7 Parameter Measurement Information

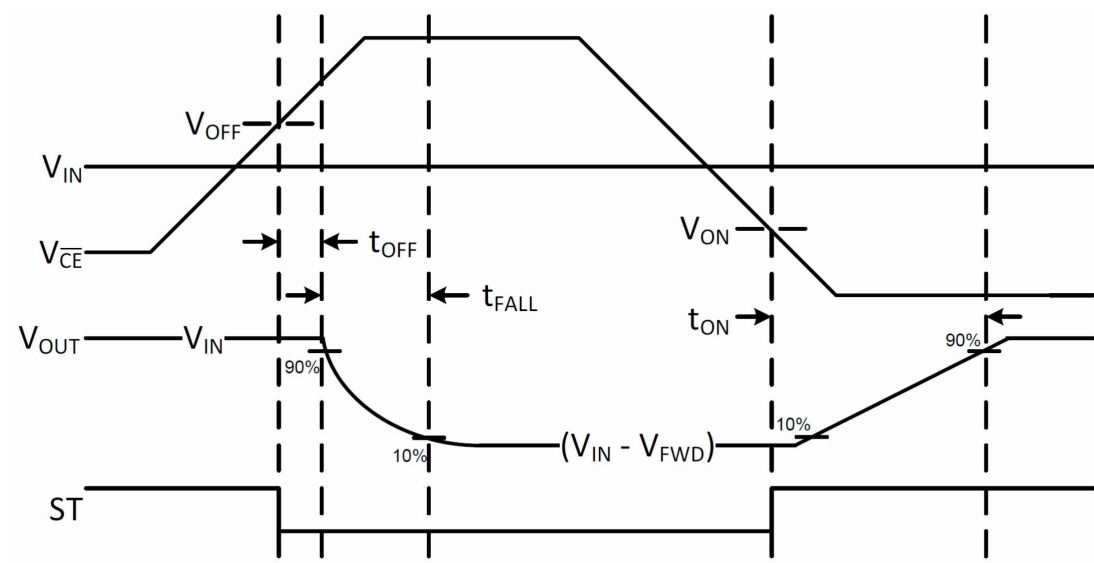


图 7-1. Timing Diagram

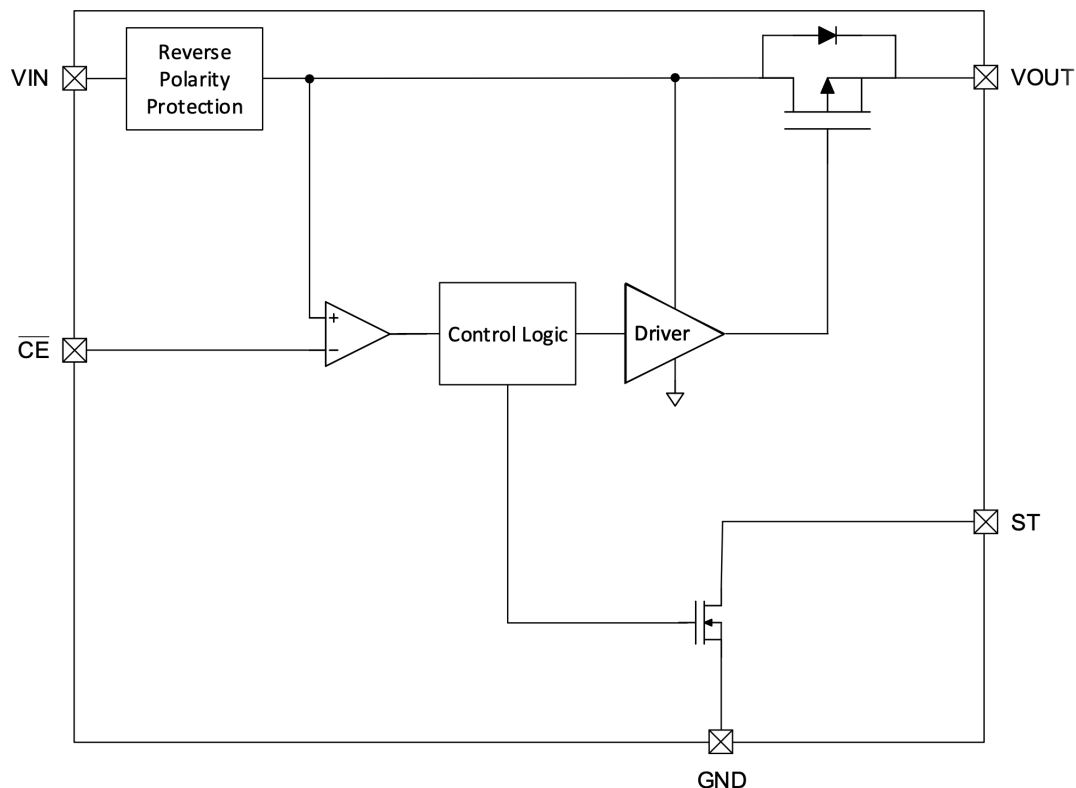
8 Detailed Description

8.1 Overview

The LM66100-Q1 is a Single-Input, Single-Output (SISO) integrated ideal diode that contains a P-channel MOSFET to minimize the voltage drop from input to output. The LM66100-Q1 can operate over an input voltage range of 1.5 V to 5.5 V and support a maximum continuous current of 1.5 A.

The chip enable works by comparing the $\overline{CE}$ pin voltage to the input voltage. When the $\overline{CE}$ pin voltage is higher than V_{IN} by 80 mV, the device is disabled and the MOSFET is off. When the $\overline{CE}$ pin voltage is lower than V_{IN} by 250 mV, the MOSFET is on. The LM66100-Q1 also comes with reverse polarity protection (RPP) that protects against events where the V_{IN} and GND terminals are swapped.

8.2 Functional Block Diagram



8.3 Feature Description

8.3.1 Reverse Polarity Protection (RPP)

In the event a negative input voltage is applied, the ideal diode stays off and prevent current flow to protect the system load. For a stand-alone, always on application, $\overline{CE}$ can be tied to GND so it does not go negative with respect to GND. See 图 8-1.

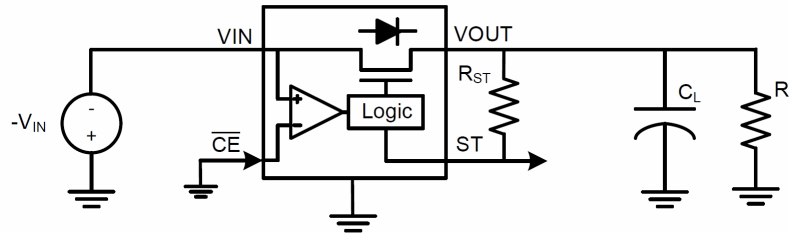


图 8-1. RPP Protection Circuit

8.3.2 Always-ON Reverse Current Blocking (RCB)

By connecting the $\overline{CE}$ pin to VOUT, this allows the comparator to detect reverse current flow through the switch. If the output is forced above the selected input by V_{OFF} , the channel switches off to stop the reverse current I_{RCB} within t_{OFF} . Once the output falls below V_{IN} by V_{ON} , the device turns back on.

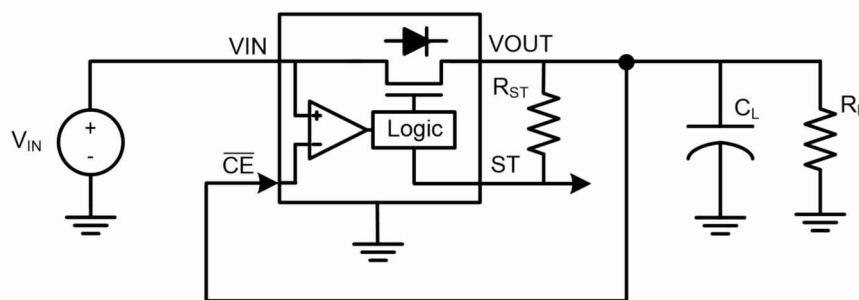


图 8-2. RCB Circuit

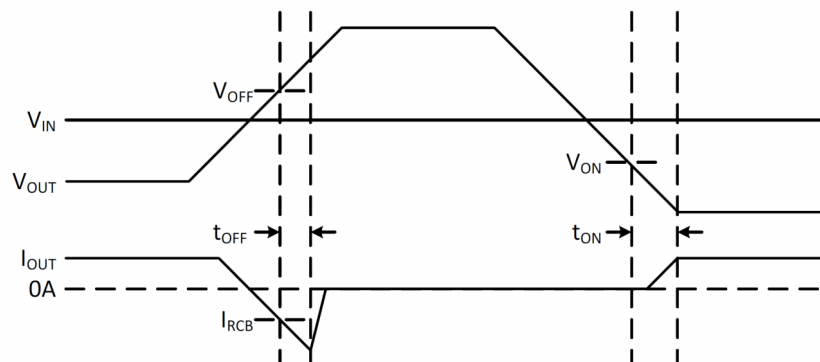


图 8-3. RCB Waveforms

8.4 Device Functional Modes

表 8-1 summarizes the Device Functional Modes:

表 8-1. Device Functional Modes

State	IN-to-OUT	Power Dissipation	ST State
OFF	Diode	$I_{OUT} \times V_{FWD}$	L
ON	Switch	$I_{OUT}^2 \times R_{ON}$	H

9 Application and Implementation

备注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

The LM66100-Q1 Ideal Diode can be used in a variety of stand-alone and multi-channel applications.

9.2 Typical Applications

9.2.1 Dual Ideal Diode ORing

Two LM66100-Q1 Ideal Diodes can be used together for ORing between two power supplies.

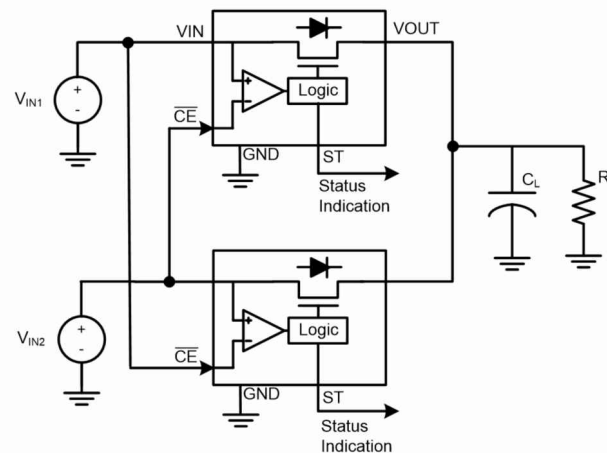


图 9-1. Dual Ideal Diode ORing

9.2.1.1 Design Requirements

Design a circuit that allows the highest input voltage to power a downstream system while providing reverse current protection.

9.2.1.2 Detailed Design Procedure

This circuit ties the $\overline{CE}$ of each device to the opposite power source. In this configuration, the highest supply is always selected using a make-before-break logic. This selection prevents any reverse current flow between the supplies and avoids the need of a dedicated reverse current blocking comparator. For ORing applications that need RPP, TI recommends to use a series resistor (R_{CE}) to limit the current into the $\overline{CE}$ pin during a negative voltage event.

9.2.1.3 Application Curves

The below scope shot shows the output voltage (VOUT) being initially powered by VIN1. When VIN2 is applied, it powers VOUT because it is a higher voltage. When VIN2 is removed, VOUT is once again powered by VIN1.

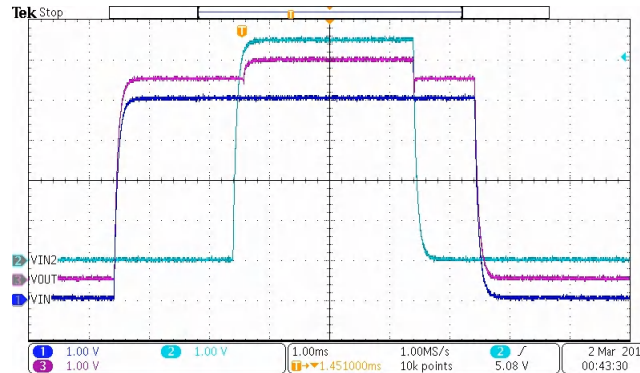


图 9-2. Dual Ideal Diode ORing Behavior

9.2.2 Dual Ideal Diode ORing for Continuous Output Power

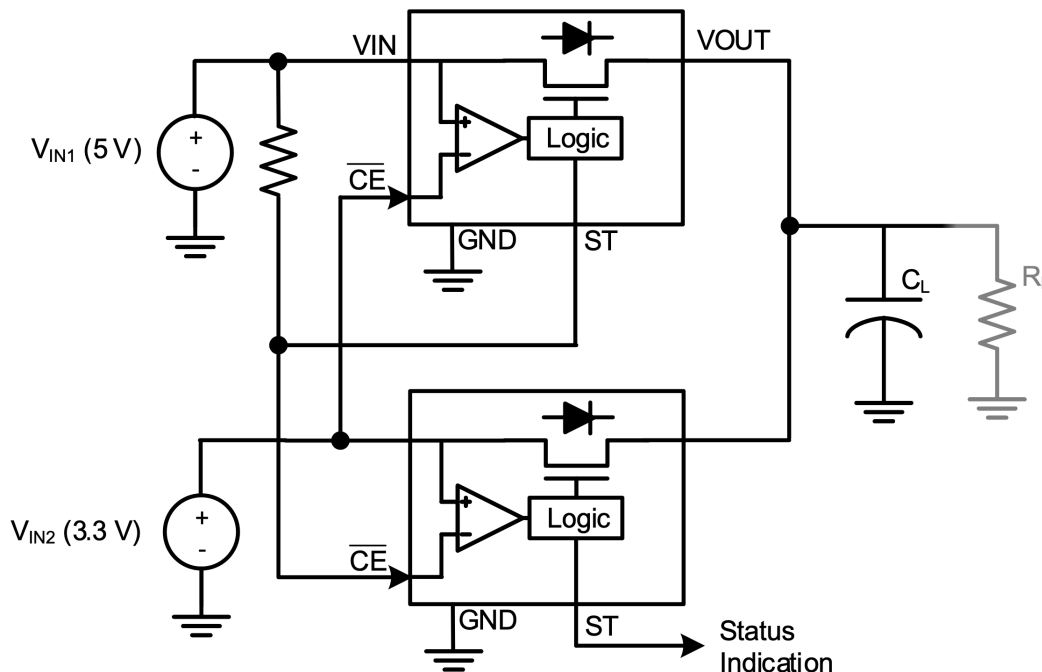


图 9-3. Dual Ideal Diode ORing for Continuous Output Power

9.2.2.1 Design Requirements

The shortcoming of the previous implementation happens when both input voltages are the same for a long period of time. Then, both devices completely turn off, powering down the output load. To avoid this case, use the status output from the priority supply and a pullup resistor, causing both devices to switchover at the same time. For ORing applications that need RPP, TI recommends to use a series resistor (R_{CE}) to limit the current into the $\overline{CE}$ pin during a negative voltage event.

9.2.2.2 Application Curves

The figures below show the switchover performance between VIN1 and VIN2.

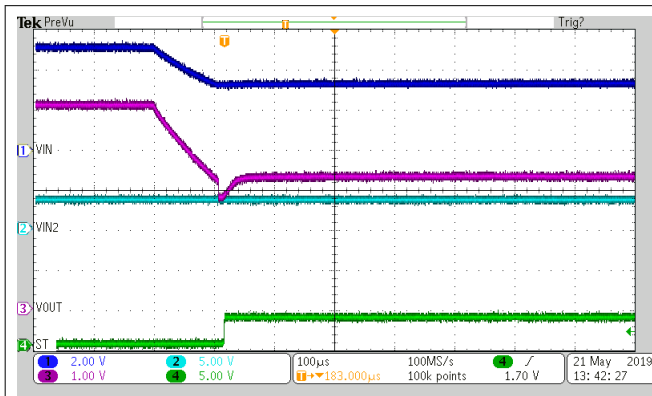


图 9-4. Switchover From VIN1 (5 V) to VIN2 (3.3 V)

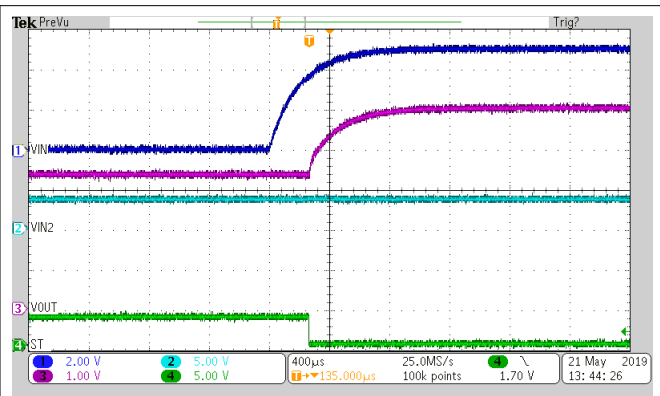


图 9-5. Switchover From VIN2 (3.3 V) to VIN1 (5 V)

9.2.3 ORing with Discrete MOSFET

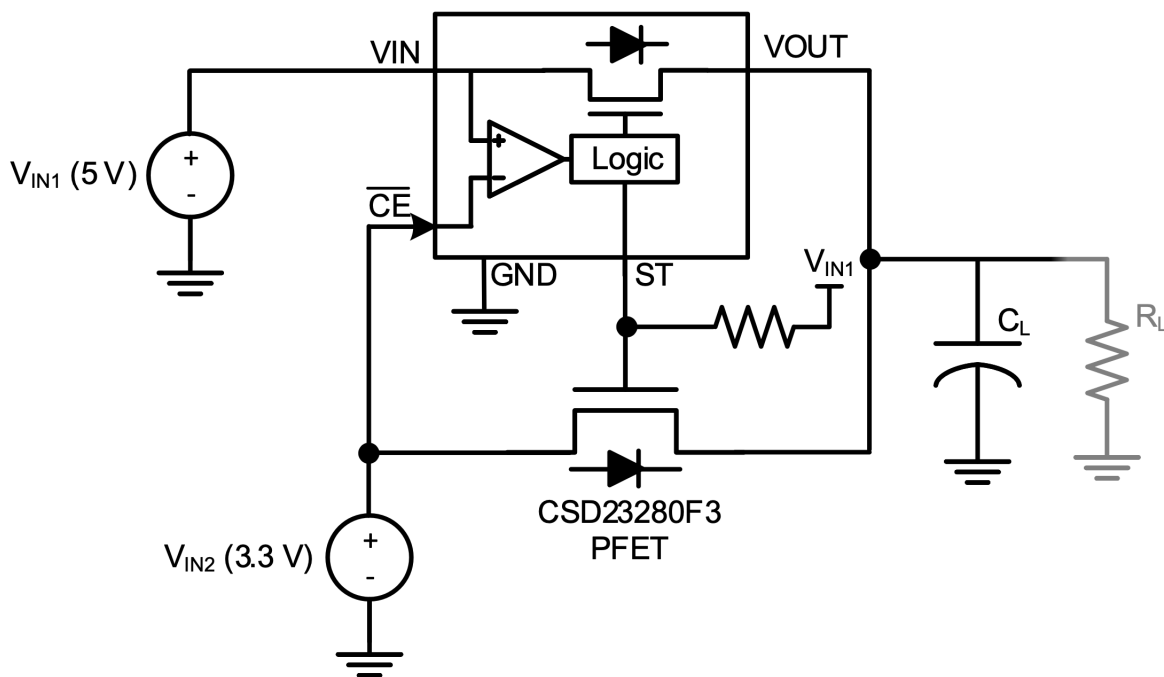


图 9-6. ORing with a Discrete MOSFET

9.2.3.1 Design Requirements

Similar to the Dual Ideal Diode circuit, the Status Output can also be used to control a discrete P-Channel MOSFET. This action can be useful in applications that want to minimize the leakage current on the secondary supply, such as battery backup systems. This configuration can also be used on systems that require a lower RON on the secondary rail, useful for higher current applications.

When the Ideal Diode path is enabled, the status is Hi-Z and pulls up the gate of the external PFET to keep it off. When the main supply (VIN1) drops such that backup supply (VIN2) is higher than VIN1, the ideal diode is disabled and pulls the ST pin and the PFET gate low to turn on the discrete MOSFET path.

9.2.3.2 Application Curves

The figures below show the switchover performance between VIN1 and VIN2.

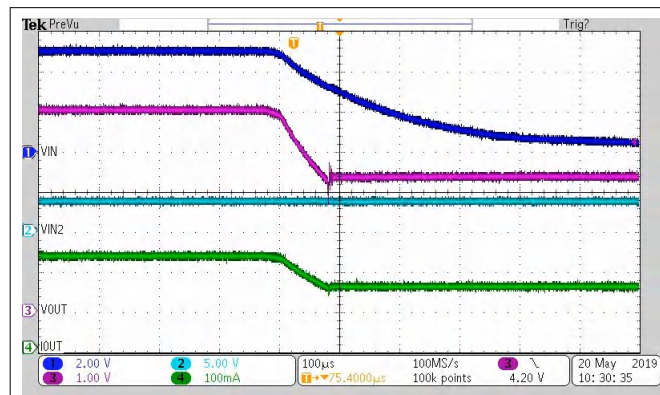


图 9-7. Switchover From VIN1 5 V to VIN2 3.3 V

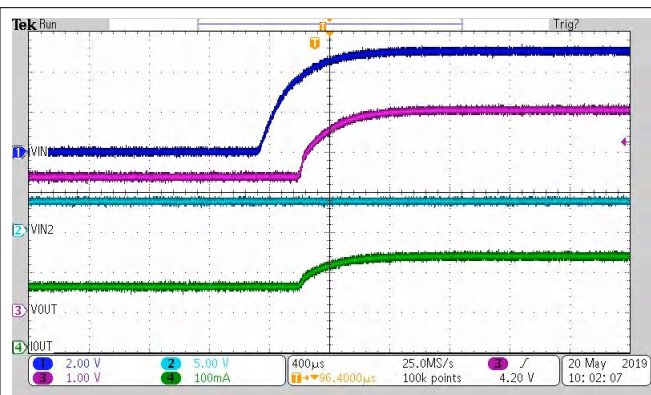


图 9-8. Switchover From VIN2 3.3 V to VIN1 5 V

10 Power Supply Recommendations

The device is designed to operate with a VIN range of 1.5 V to 5.5 V. The VIN power supply must be well regulated and placed as close to the device terminal as possible. The power supply must be able to withstand all transient load current steps. In most situations, using an input capacitance (CIN) of 1 μ F is sufficient to prevent the supply voltage from dipping when the switch is turned on. In cases where the power supply is slow to respond to a large transient current or large load current step, additional bulk capacitance can be required on the input.

11 Layout

11.1 Layout Guidelines

For best performance, all traces must be as short as possible. To be most effective, place the input and output capacitors close to the device to minimize the effects that parasitic trace inductances can have on normal operation. Using wide traces for VIN, VOUT, and GND helps minimize the parasitic electrical effects.

11.2 Layout Example

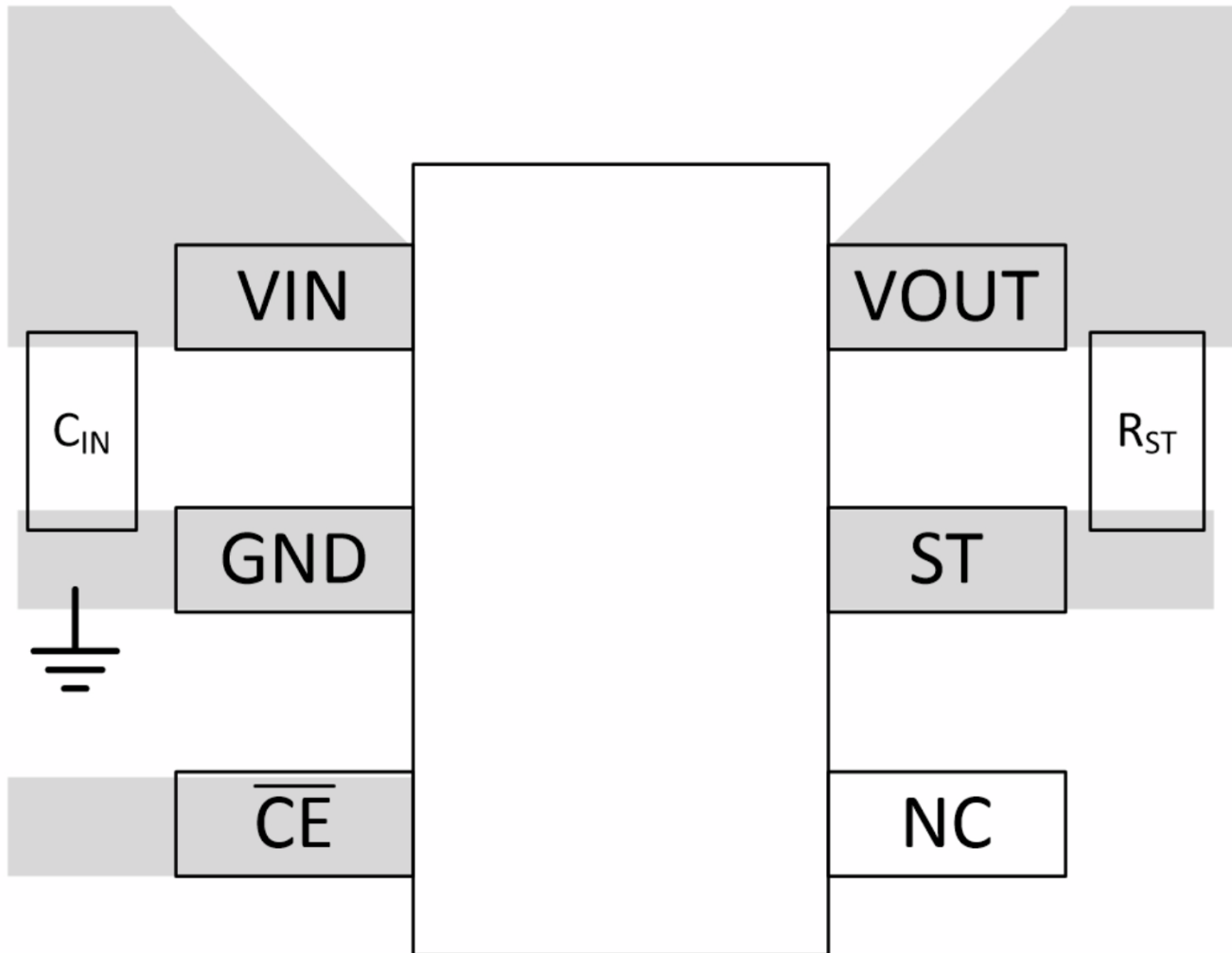


图 11-1. LM66100-Q1 Layout Example

12 Device and Documentation Support

12.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.2 支持资源

TI E2E™ 支持论坛是工程师的重要参考资料，可直接从专家获得快速、经过验证的解答和设计帮助。搜索现有解答或提出自己的问题可获得所需的快速设计帮助。

链接的内容由各个贡献者“按原样”提供。这些内容并不构成 TI 技术规范，并且不一定反映 TI 的观点；请参阅 TI 的《使用条款》。

12.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

所有商标均为其各自所有者的财产。

12.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.5 术语表

TI 术语表 本术语表列出并解释了术语、首字母缩略词和定义。

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
LM66100QDCKRQ1	Active	Production	SC70 (DCK) 6	3000 LARGE T&R	Yes	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	1IW
LM66100QDCKRQ1.A	Active	Production	SC70 (DCK) 6	3000 LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	1IW

⁽¹⁾ **Status:** For more details on status, see our [product life cycle](#).

⁽²⁾ **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

⁽⁴⁾ **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer:The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

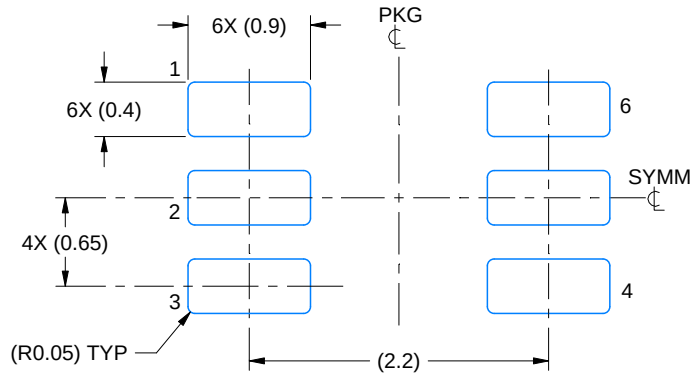
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF LM66100-Q1 :

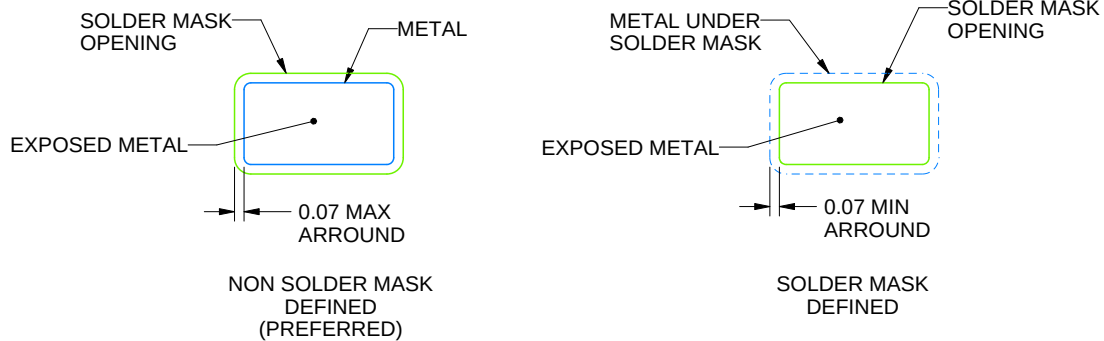
- Catalog : [LM66100](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:18X

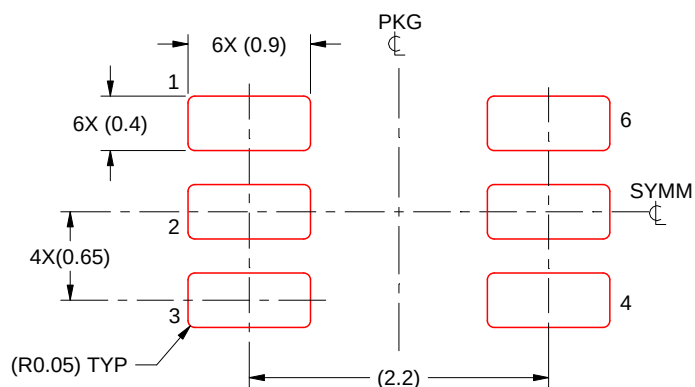


SOLDER MASK DETAILS

4214835/D 11/2024

NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.
6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOLDER PASTE EXAMPLE
 BASED ON 0.125 THICK STENCIL
 SCALE:18X

4214835/D 11/2024

NOTES: (continued)

7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
8. Board assembly site may have different recommendations for stencil design.

重要通知和免责声明

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